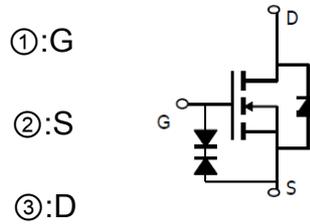


N-Channel Enhancement Mode Field Effect Transistor

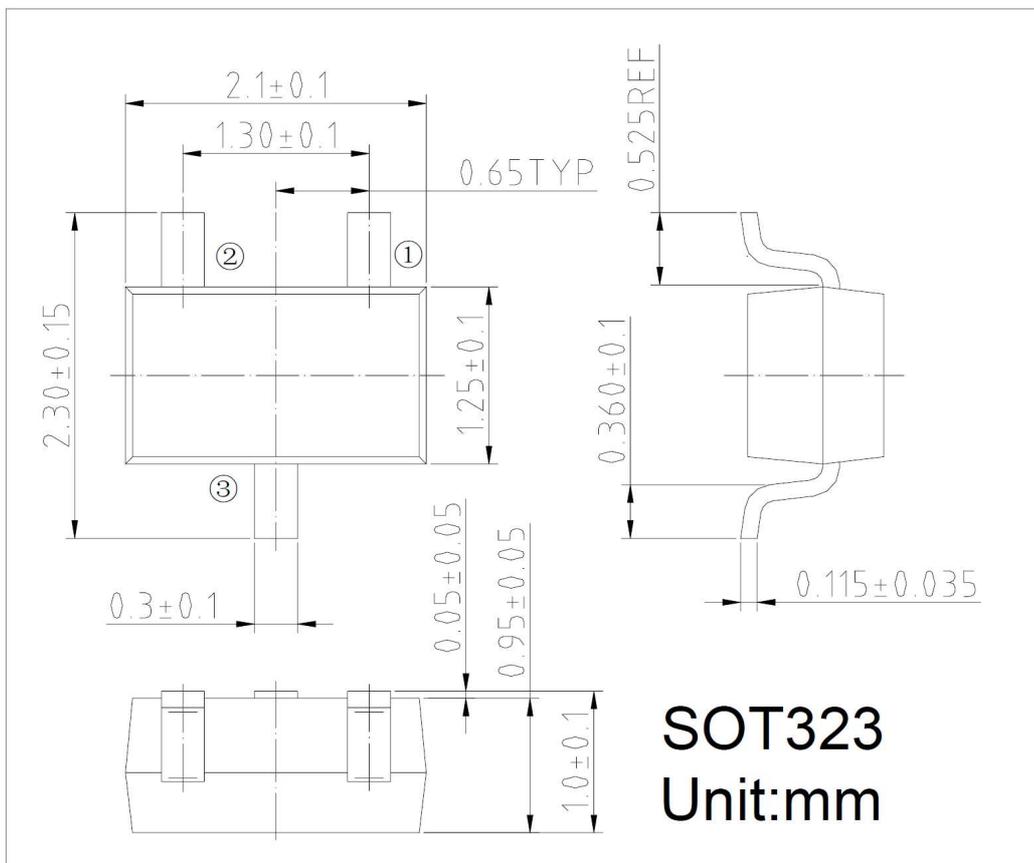
- Features**

- Low On-Resistance
- Fast Switching Speed
- Low-voltage drive
- Easily designed drive circuits
- ESD Protected

- Pin Configurations**



- Package Information**



- Absolute Maximum Ratings @ $T_A=25^\circ\text{C}$ unless otherwise noted**

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V_{bss}	60	V
Gate-Source Voltage	V_{gss}	± 20	V



RCR1514ESH

Drain Current (Continuous)	$T_A=25^\circ\text{C}$	I_D	200	mA
Drain Current (Pulse)		I_{DM}^*1	800	mA
Power Dissipation	$T_A=25^\circ\text{C}$	P_D^*2	200	mW
Operating Temperature/ Storage Temperature		T_{J}/T_{STG}	-55~150	$^\circ\text{C}$

*1 $P_w \leq 10 \mu\text{s}$, Duty cycle $\leq 1\%$

*2 When mounted on a 1*0.75*0.062 inch glass epoxy board

● Electrical Characteristics @ $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D=10\mu\text{A}$	60	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60V, V_{GS} = 0V$	--	--	1	μA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=3V, I_{DS}=100\mu\text{A}$	0.8	1.4	2	V
Gate Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	--	--	± 1	μA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = 4V, I_D=10\text{mA}$	--	5	8	Ω
		$V_{GS} = 2.5V, I_D=1\text{mA}$	--	7	13	Ω
Forward Transconductance	g_{FS}^*	$V_{DS}=3V, I_D=10\text{mA}$	--	20	--	mS
Switching						
Turn-on Delay Time	$t_{d(on)}^*$	$I_D=10\text{mA}, V_{DS} = 5V,$	--	15	--	ns
Turn-off Delay Time	$t_{d(off)}^*$	$V_{GS}=5V, R_L=500\Omega, R_G=10\Omega$	--	80	--	ns
Dynamic						
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=5V, f=1.0\text{MHz}$	--	13	--	pF
Output Capacitance	C_{oss}		--	9	--	pF
Reverse Transfer Capacitance	C_{rss}		--	4	--	pF

* $P_w \leq 300 \mu\text{s}$, Duty cycle $\leq 1\%$

● Typical Performance Characteristics

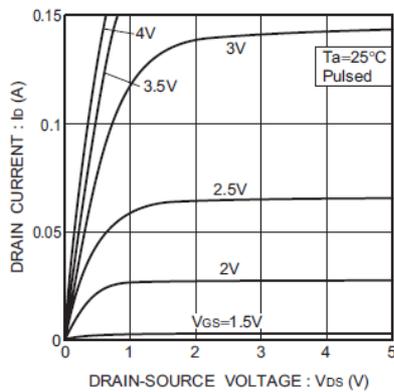


Fig.1 Typical output characteristics

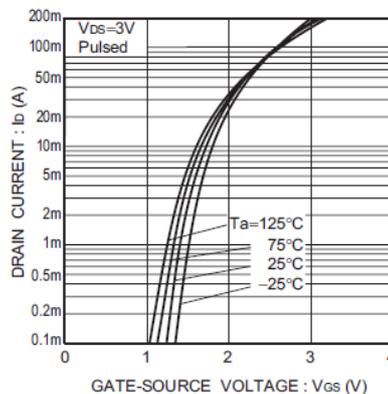


Fig.2 Typical transfer characteristics

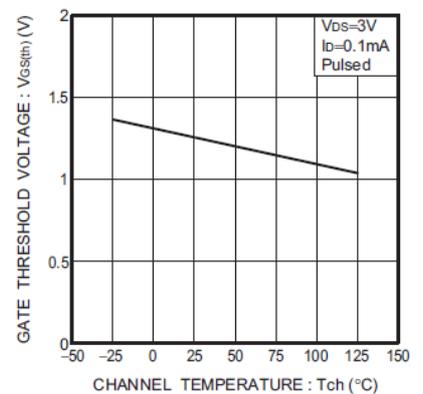


Fig.3 Gate threshold voltage vs. channel temperature

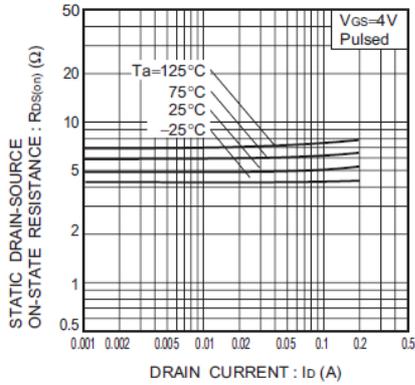


Fig.4 Static drain-source on-state resistance vs. drain current (I)

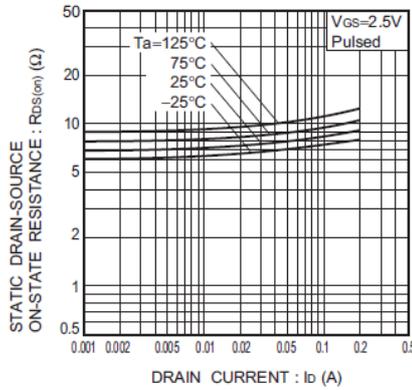


Fig.5 Static drain-source on-state resistance vs. drain current (II)

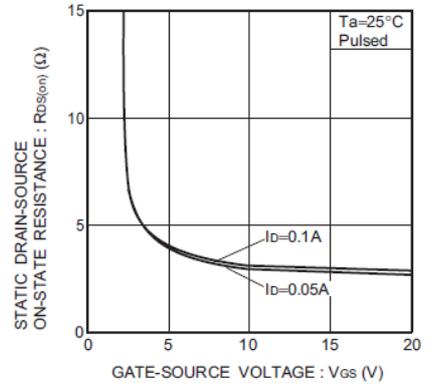


Fig.6 Static drain-source on-state resistance vs. gate-source voltage

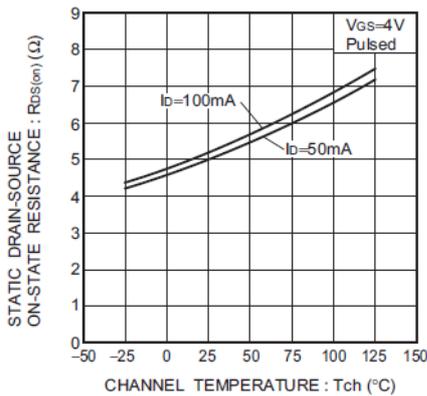


Fig.7 Static drain-source on-state resistance vs. channel temperature

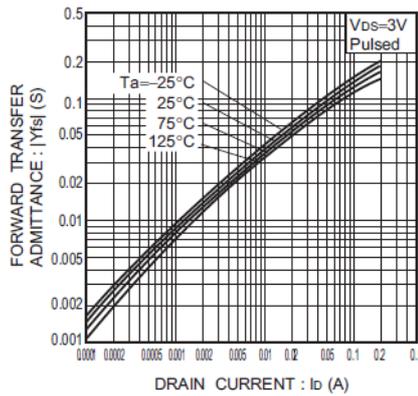


Fig.8 Forward transfer admittance vs. drain current

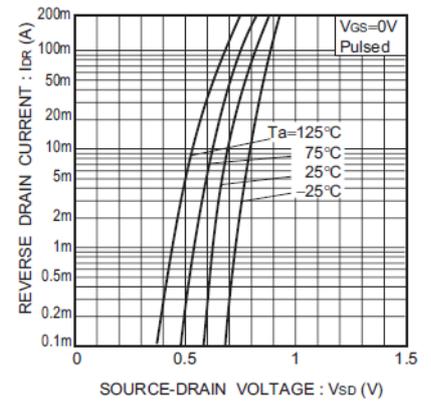


Fig.9 Reverse drain current vs. source-drain voltage (I)

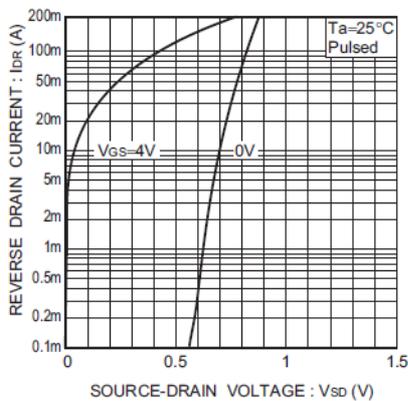


Fig.10 Reverse drain current vs. source-drain voltage (II)

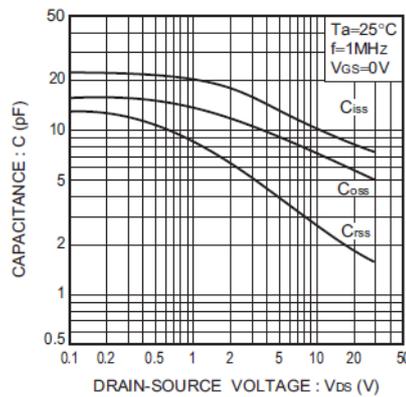


Fig.11 Typical capacitance vs. drain-source voltage

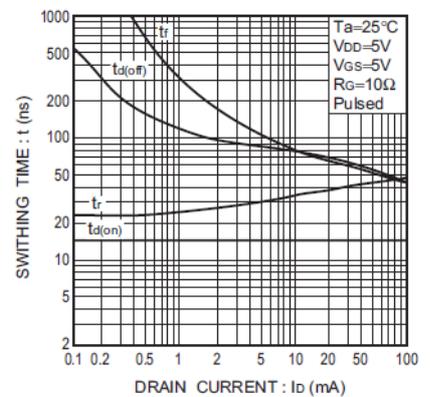


Fig.12 Switching characteristics (See Figures 13 and 14 for the measurement circuit and resultant waveforms)



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